

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277
Takao KAMOSHIMA, et al. : Confirmation Number:
Serial No.: : Group Art Unit:
Filed: September 09, 2003 : Examiner: Unknown
For: INTERCONNECTION STRUCTURE

INFORMATION DISCLOSURE STATEMENT

Mail Stop IDS
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P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

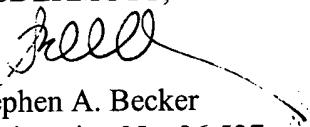
The relevance of the references listed on attached Form 1449 is discussed in the present specification.

Serial No.:

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)			ATTY. DOCKET NO. 67161-098	SERIAL NO.			
			APPLICANT Takao KAMOSHIMA, et al.				
			FILING DATE September 09, 2003	GROUP			
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
		US					
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FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number 4-Kind Codes (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
		JP P2001-156073A	06/08/2001	CHARTERED SEMICONDUCTOR MFG LTD		Yes	No
		JP 7-201851	08/04/1995	FUJITSU LTD		(Japan w/English Abstract)	
		JP P2001-345325A	12/14/2001	NEC KYUSHU LTD		(Japan w/English Abstract)	
						(Japan w/English Abstract)	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
		"Stress-Induced Voiding Under Vias Connected To Wide Cu Metal Leads", E.T. Ogawa et al., IEEE 02CH37320, 40th Annual International Reliability Physics Symposium, Dallas, Texas, 2002, pp. 312-321					
EXAMINER				DATE CONSIDERED			

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1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.